

Notice of References Cited	Application/Control No. 10/737,339	Applicant(s)/Patent Under Reexamination FANG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0172146 A1	11-2002	WU et al.	370/208
*	B	US-2002/0181389 A1	12-2002	Giannakis et al.	370/208
*	C	US-2002/0181549 A1	12-2002	Linnartz et al.	375/142
*	D	US-2003/0171128 A1	09-2003	Tandai et al.	455/502
*	E	US-2004/0047368 A1	03-2004	Xu, Jin Biao	370/509
*	F	US-2004/0141548 A1	07-2004	Shattil, Steve J.	375/146
*	G	US-2004/0131011 A1	07-2004	Sandell et al.	370/210
*	H	US-2004/0184398 A1	09-2004	Walton et al.	370/203
*	I	US-6,934,340 B1	08-2005	Dollard, Michael S.	375/260
*	J	US-2005/0259568 A1	11-2005	Yeh et al.	370/208
*	K	US-7,218,693 B2	05-2007	Troulis, Markos G.	375/346
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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